

INFORMATION DISCLOSURE CITATION IN AN APPLICATION <i>(Use several sheets if necessary)</i>				Docket Number (Optional) 130894-2 60SD		Application Number 1016995024	
				Applicant GENERAL ELECTRIC COMPANY			
				Filing Date October 31, 2003		Group Art Unit	
U. S. PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
	6,273,948	2001-08-14	Porowski et al.	117	077		
	2,941,241	1960-06-01	Strong	425	077		
	4,523,478	1985-06-18	Zacharias	073	861		
	6,375,446	2002-04-23	Leonelli	425	077		
	2003/0140845	2003-07-31	D'Evelyn et al.	117	008		
	5236674	1993-08-1	Frushour	422	241		
FOREIGN PATENT DOCUMENTS							
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION	
						YES	NO
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER			DATE CONSIDERED				
			11/14/03				

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AUG 16 2004

Sheet 1 of 1

Form PTO-1449
(Reproduced)INFORMATION DISCLOSURE CITATION
IN AN APPLICATION
(Use several sheets if necessary)Docket Number (Optional)
130894-2Application Number
10/699504Applicant
GENERAL ELECTRIC COMPANYFiling Date
10/31/2003Group Art Unit
1765

U. S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	US2003/140845	07/31/03	D'Evelyn et al.			

FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION	
						YES	NO
	EP0220462	05/06/87	Europe				
	EP0157393	10/09/85	Europe				
	GB922619	04/03/63	Great Britian				
	FR1306951	10/19/62	France				
	WO 01/36080	05/25/01	World				
	EP0152726	08/28/85	Eurone				

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

	Hanser A D, et al: "Growth, doping and characterization of epitaxial thin films and patterned structures of AlN, GaN, and Al _x Ga _{1-x} N"; XP004364890
	Lawniczak-Jablonska K. et al.: "Polarization dependent x-ray absorption studies of the chemical bonds anisotropy in wurtzite GaN grown at different conditions"; XP004304294

EXAMINER	DATE CONSIDERED
	11/14/08

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.